

MOS INTEGRATED CIRCUIT $\mu PD442012L-X$

2M-BIT CMOS STATIC RAM 128K-WORD BY 16-BIT EXTENDED TEMPERATURE OPERATION

Description

The μ PD442012L-X is a high speed, low power, 2,097,152 bits (131,072 words by 16 bits) CMOS static RAM.

The μ PD442012L-X has two chip enable pins (/CE1, CE2) to extend the capacity.

★ The μ PD442012L-X is packed in 48-pin plastic TSOP (I) (Normal bent).

Features

- 131,072 words by 16 bits organization
- Fast access time: 70, 85, 100, 120, 150, 200 ns (MAX.)
- Byte data control: /LB (I/O1 I/O8), /UB (I/O9 I/O16)
- Low voltage operation

(B version: Vcc = 2.7 to 3.6 V, C version: Vcc = 2.2 to 3.6 V, D version: Vcc = 1.8 to 3.6 V)

• Low Vcc data retention

(B version: 2.0 V (MIN.), C version: 1.5 V (MIN.), D version: 1.5 V (MIN.))

- Operating ambient temperature: T_A = -25 to +85 °C
- Output Enable input for easy application
- Two Chip Enable inputs: /CE1, CE2

Part number	Access time	Operating supply	Operating ambient		Supply current	
	ns (MAX.)	voltage	temperature	At operating	At standby	At data retention
		V	°C	mA (MAX.)	μA (MAX.)	μA (MAX.)
μPD442012L-BxxX	70, 85	2.7 to 3.6	-25 to +85	35	4	4
μPD442012L-CxxX	100, 120	2.2 to 3.6				
μPD442012L-DxxX ^{Note}	150, 200	1.8 to 3.6				

Note Under development

The information in this document is subject to change without notice. Before using this document, please confirm that this is the latest version.

Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

★ Ordering Information

Part number	Package	Access time	Operating	Operating	Remark
		ns (MAX.)	supply voltage	temperature	
			V	°C	
μPD442012LGY-B70X-MJH	48-PIN PLASTIC TSOP (I)	70	2.7 to 3.6	-25 to +85	B version
μPD442012LGY-B85X-MJH	(12×18) (Normal bent)	85			
μPD442012LGY-C10X-MJH		100	2.2 to 3.6		C version
μPD442012LGY-C12X-MJH		120			
μPD442012LGY-D15X-MJH Note		150	1.8 to 3.6		D version
μPD442012LGY-D20X-MJH Note		200			

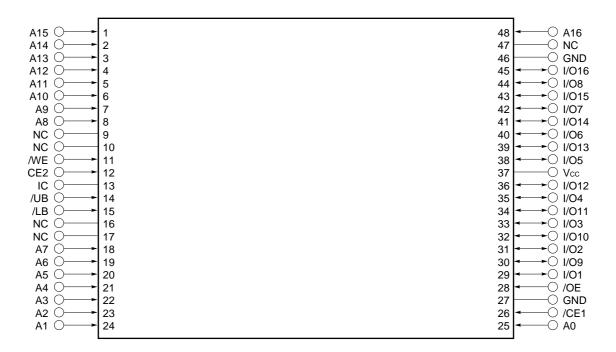
Note Under development

★ Pin Configuration (Marking Side)

/xxx indicates active low signal.

48-PIN PLASTIC TSOP (I) (12×18) (Normal bent)

[μ PD442012LGY-BxxX-MJH] [μ PD442012LGY-CxxX-MJH] [μ PD442012LGY-DxxX-MJH]



A0 - A16 : Address inputs
I/O1 - I/O16 : Data inputs / outputs
/CE1, CE2 : Chip Enable 1, 2
/WE : Write Enable
/OE : Output Enable
/LB, /UB : Byte data select
Vcc : Power supply
GND : Ground

NC : No Connection

IC Note : Internal Connection

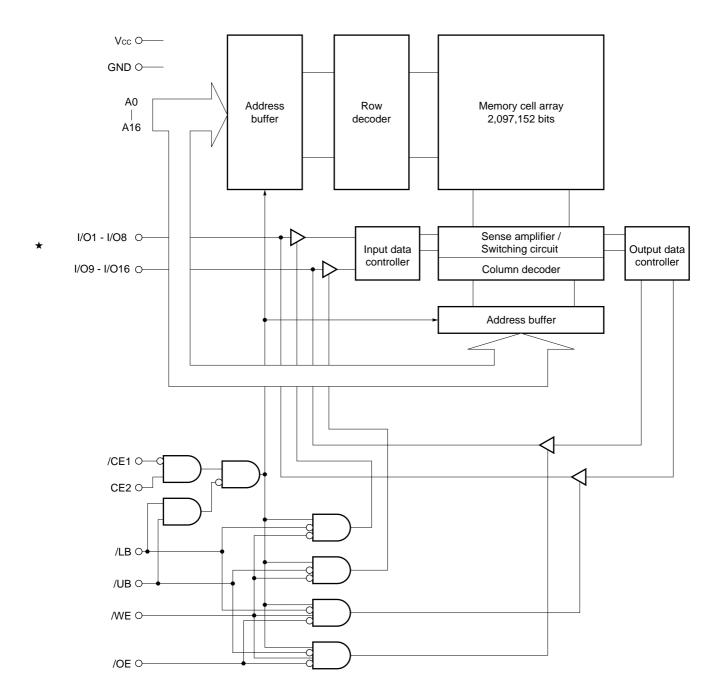
Note Leave this pin unconnected or connect to GND.

Remark Refer to **Package Drawing** for the 1-pin index mark.

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Block Diagram



Truth Table

/CE1	CE2	/OE	/WE	/LB	/UB	Mode	1/4	0	Supply current
							I/O1 - I/O8	I/O9 - I/O16	
Н	×	×	×	×	×	Not selected	High impedance	High impedance	lsв
×	L	×	×	×	×				
L	Н	Н	Η	×	×	Output disable	High impedance	High impedance	ICCA
		L	Н	L	L	Word read	D оит	D оит	
				L	Н	Lower byte read	D оит	High impedance	
				Н	L	Upper byte read	High impedance	D оит	
		×	L	L	L	Word write	Din	DIN	
				L	Н	Lower byte write	Din	High impedance	
				Н	L	Upper byte write	High impedance	Din	
×	×	×	×	Н	Н	Not selected	High impedance	High impedance	lsв

Remark ×: VIH or VIL

Electrical Specifications

Absolute Maximum Ratings

Parameter	Symbol	Condition	Rating	Unit
Supply voltage	Vcc		-0.5 Note to +4.0	V
Input / Output voltage	VT		-0.5 Note to Vcc+0.4 (4.0 V MAX.)	٧
Operating ambient temperature	TA		-25 to +85	°C
Storage temperature	Tstg		-55 to +125	°C

Note -3.0 V (MIN.) (Pulse width: 30 ns)

Caution Exposing the device to stress above those listed in Absolute Maximum Rating could cause permanent damage. The device is not meant to be operated under conditions outside the limits described in the operational section of this specification. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability.

Recommended Operating Conditions

Parameter	Symbol	Condition	μPD4420	μPD442012L-BxxX		12L-CxxX	μPD4420	Unit	
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Supply voltage	Vcc		2.7	3.6	2.2	3.6	1.8	3.6	V
High level input voltage	VIH	2.7 V ≤ Vcc ≤ 3.6 V	2.4	Vcc+0.4	2.4	Vcc+0.4	2.4	Vcc+0.4	٧
		2.2 V ≤ Vcc < 2.7 V	-	-	2.0	Vcc+0.3	2.0	Vcc+0.3	
		1.8 V ≤ Vcc < 2.2 V	-	-	-	-	1.6	Vcc+0.2	
Low level input voltage	VIL		-0.3 Note	+0.5	-0.3 Note	+0.3	-0.3 Note	+0.2	٧
Operating ambient temperature	TA		-25	+85	-25	+85	-25	+85	°C

Note -1.5 V (MIN.) (Pulse width: 30 ns)

Capacitance (T_A = 25 °C, f = 1 MHz)

Parameter	Symbol	Test condition	MIN.	TYP.	MAX.	Unit
Input capacitance	Cin	Vin = 0 V			8	pF
Input / Output capacitance	C _{I/O}	V1/0 = 0 V			10	pF

Remarks 1. VIN: Input voltage

Vi/o: Input / Output voltage

2. These parameters are periodically sampled and not 100% tested.



DC Characteristics (Recommended Operating Conditions Unless Otherwise Noted)

Parameter	Symbol	Test condition	on	Vo	cc ≥ 2. 7	7 V	Vo	:c ≥ 2. 2	2 V	Vo	c ≥ 1.8	3 V	Unit
				μ PD4	42012L	-BxxX	μPD4	42012L	-CxxX	μPD4	42012L	-DxxX	
				MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
Input leakage current	lu	$V_{IN} = 0 \text{ V to Vcc}$		-1.0		+1.0	-1.0		+1.0	-1.0		+1.0	μΑ
I/O leakage	ILO	Vi/o = 0 V to Vcc, /CE1 = ViH or				+1.0	-1.0		+1.0	-1.0		+1.0	μΑ
current		CE2 = VIL or /WE = VIL	or /OE = VIH										
Operating	ICCA1	/CE1 = VIL, CE2 = VIH,			-	35		-	35		-	35	mA
supply current		Minimum cycle time,	Vcc ≤ 2.7 V		-	-		-	20		-	20	
		I _{1/0} = 0 mA	Vcc ≤ 2.2 V		-	-		-	_		_	15	
	ICCA2	/CE1 = VIL, CE2 = VIH,			-	10		-	10		-	10	
		I _{1/0} = 0 mA	Vcc ≤ 2.7 V		_	_		_	8		_	8	
			Vcc ≤ 2.2 V		_	_		_	_		_	6	
	Іссаз	/CE1 ≤ 0.2 V, CE2 ≥ Vo	cc - 0.2 V,		_	8		_	8		_	8	
		Cycle = 1 MHz, I _V o = 0	mA,										
		$V_{IL} \leq 0.2 V$,	Vcc ≤ 2.7 V		_	_		_	6		_	6	
		V _{IH} ≥ V _{CC} − 0.2 V	Vcc ≤ 2.2 V		-	-		-	_		-	5	
Standby	Isa	/CE1 = VIH or CE2 = VIL	or		_	0.6		_	0.6		_	0.6	mA
supply current		$/LB = /UB = V_{IH},$	Vcc ≤ 2.7 V		_	_		_	0.6		_	0.6	
		/CE1, CE2 = VIH or VIL	Vcc ≤ 2.2 V		-	-		-	-		-	0.6	
	I _{SB1}	/CE1 ≥ Vcc - 0.2 V,			0.3	4		0.3	4		0.3	4	μΑ
		CE2 ≥ Vcc - 0.2 V	Vcc ≤ 2.7 V		-	-		0.25	3.5		0.25	3.5	
			Vcc ≤ 2.2 V		_	_		_	_		0.2	3	
	I _{SB2}	CE2 ≤ 0.2 V			0.3	4		0.3	4		0.3	4	
			Vcc ≤ 2.7 V		-	-		0.25	3.5		0.25	3.5	
			Vcc ≤ 2.2 V		-	-		-	-		0.2	3	
	I _{SB3}	/LB = /UB ≥ Vcc - 0.2 V	',		0.3	4		0.3	4		0.3	4	
		$/CE1 \le 0.2 V$,	Vcc ≤ 2.7 V		_	_		0.25	3.5		0.25	3.5	
		$\text{CE2} \geq \text{Vcc} - 0.2 \text{ V}$	Vcc ≤ 2.2 V		_	_		_	_		0.2	3	
High level	Vон	Iон = -0.5 mA		2.4			2.4			2.4			٧
output voltage			Vcc ≤ 2.7 V	-			1.8			1.8			
			Vcc ≤ 2.2 V	-			-			1.5			
Low level	Vol	IoL = 1.0 mA				0.4			0.4			0.4	V
output voltage													

Remarks 1. VIN: Input voltage

Vi/o: Input / Output voltage

2. These DC characteristics are in common regardless of access time.

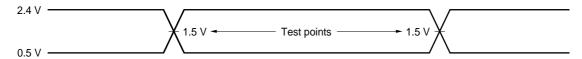


AC Characteristics (Recommended Operating Conditions Unless Otherwise Noted)

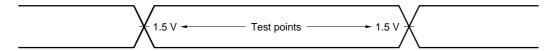
AC Test Conditions

[μ PD442012L-B70X, μ PD442012L-B85X]

Input Waveform (Rise and Fall Time ≤ 5 ns)



Output Waveform

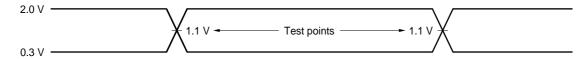


Output Load

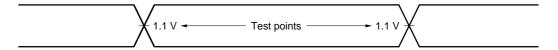
1TTL + 50 pF

[μ PD442012L-C10X, μ PD442012L-C12X]

Input Waveform (Rise and Fall Time ≤ 5 ns)



Output Waveform

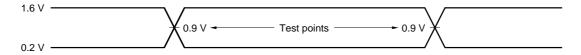


Output Load

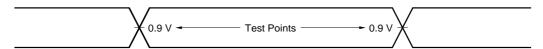
1TTL + 30 pF

[μ PD442012L-D15X, μ PD442012L-D20X]

Input Waveform (Rise and Fall Time ≤ 5 ns)



Output Waveform



Output Load

1TTL + 30 pF



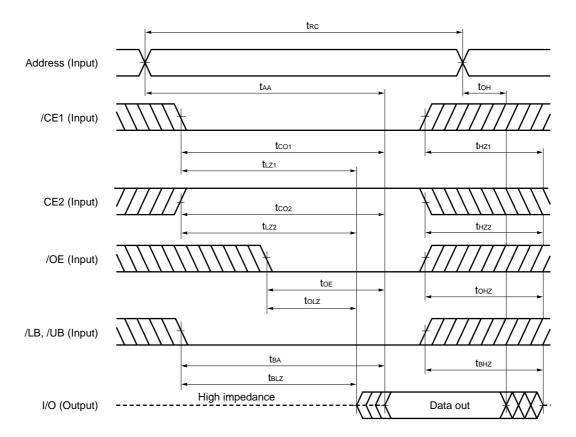
Read Cycle

Parameter	Symbol		Vcc ≥	2.7 V			Vcc ≥	2.2 V			Vcc ≥	1.8 V		Unit	Condition
		l '	42012L 70X	l '	42012L 35X	l '	42012L 10X	'	42012L 12X	l '	12012L 15X	'	12012L 20X		
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Read cycle time	trc	70		85		100		120		150		200		ns	
Address access time	t AA		70		85		100		120		150		200	ns	Note 1
/CE1 access time	t co1		70		85		100		120		150		200	ns	
CE2 access time	tco2		70		85		100		120		150		200	ns	
/OE to output valid	toe		35		40		50		60		70		100	ns	
/LB, /UB to output valid	t BA		70		85		100		120		150		200	ns	
Output hold from address change	tон	10		10		10		10		10		10		ns	
/CE1 to output in low impedance	tLZ1	10		10		10		10		10		10		ns	Note 2
CE2 to output in low impedance	t LZ2	10		10		10		10		10		10		ns	
/OE to output in low impedance	tolz	5		5		5		5		5		5		ns	
/LB, /UB to output in low impedance	t BLZ	10		10		10		10		10		10		ns	
/CE1 to output in high impedance	t HZ1		25		30		35		40		50		70	ns	
CE2 to output in high impedance	t _{HZ2}		25		30		35		40		50		70	ns	
/OE to output in high impedance	tонz		25		30		35		40		50		70	ns	
/LB, /UB to output in high impedance	tвнz		25		30		35		40		50		70	ns	

Notes 1. The output load is 1TTL + 50 pF (μ PD442012L-BxxX) or 1TTL + 30 pF (μ PD442012L-CxxX, -DxxX).

2. The output load is 1TTL + 5 pF.

Read Cycle Timing Chart



Remark In read cycle, /WE should be fixed to high level.



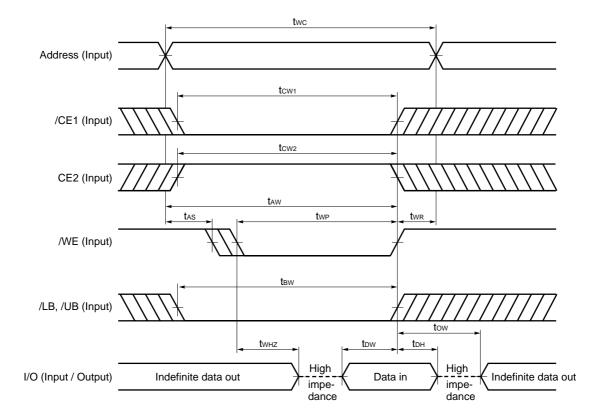
Write Cycle

Parameter	Symbol		Vcc ≥	2.7 V			Vcc ≥	2.2 V		Vcc ≥ 1.8 V				Unit	Condition
		l'	12012L 70X	l '	12012L 35X	l '	12012L 10X	l '	12012L 12X	l '	12012L 15X	l '	12012L 20X		
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Write cycle time	twc	70		85		100		120		150		200		ns	
/CE1 to end of write	tcw1	55		70		80		100		120		160		ns	
CE2 to end of write	tcw2	55		70		80		100		120		160		ns	
/LB, /UB to end of write	t BW	55		70		80		100		120		160		ns	
Address valid to end of write	taw	55		70		80		100		120		160		ns	
Address setup time	tas	0		0		0		0		0		0		ns	
Write pulse width	twp	50		55		60		85		100		140		ns	
Write recovery time	twr	0		0		0		0		0		0		ns	
Data valid to end of write	tow	30		35		40		60		80		100		ns	
Data hold time	tон	0		0		0		0		0		0		ns	
/WE to output in high impedance	twнz		25		30		35		40		50		70	ns	Note
Output active from end of write	tow	5		5		5		5		5		5		ns	

Note The output load is 1TTL + 5 pF.

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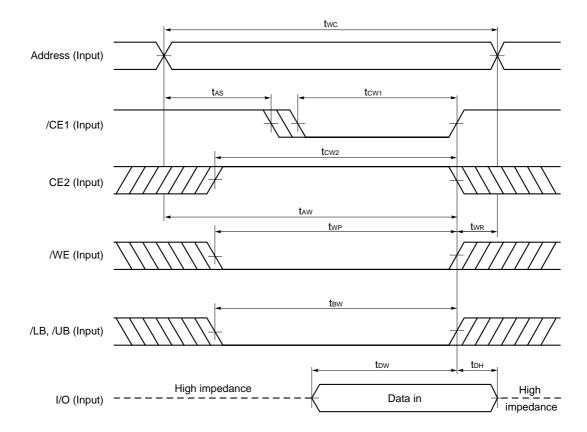
Write Cycle Timing Chart 1 (/WE Controlled)



- Cautions 1. During address transition, at least one of pins /CE1, CE2, /WE should be inactivated.
 - 2. Do not input data to the I/O pins while they are in the output state.
- **Remarks 1.** Write operation is done during the overlap time of a low level /CE1, /WE, /LB and/or /UB, and a high level CE2.
 - 2. If /CE1 changes to low level at the same time or after the change of /WE to low level, or if CE2 changes to high level at the same time or after the change of /WE to low level, the I/O pins will remain high impedance state.
 - 3. When /WE is at low level, the I/O pins are always high impedance. When /WE is at high level, read operation is executed. Therefore /OE should be at high level to make the I/O pins high impedance.



Write Cycle Timing Chart 2 (/CE1 Controlled)



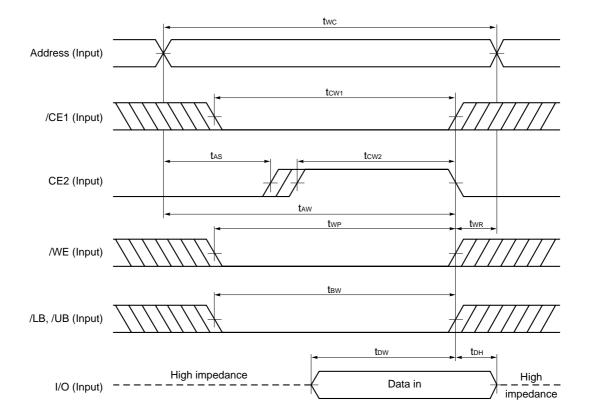
Cautions 1. During address transition, at least one of pins /CE1, CE2, /WE should be inactivated.

2. Do not input data to the I/O pins while they are in the output state.

Remark Write operation is done during the overlap time of a low level /CE1, /WE, /LB and/or /UB, and a high level CE2.



Write Cycle Timing Chart 3 (CE2 Controlled)

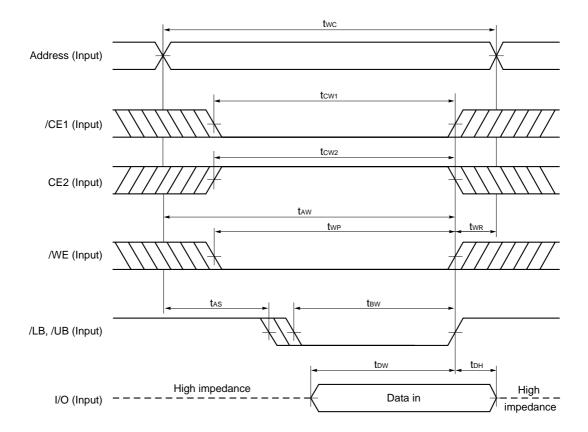


- Cautions 1. During address transition, at least one of pins /CE1, CE2, /WE should be inactivated.
 - 2. Do not input data to the I/O pins while they are in the output state.

Remark Write operation is done during the overlap time of a low level /CE1, /WE, /LB and/or /UB, and a high level CE2.



Write Cycle Timing Chart 4 (/LB, /UB Controlled)



Cautions 1. During address transition, at least one of pins /CE1, CE2, /WE should be inactivated.

2. Do not input data to the I/O pins while they are in the output state.

Remark Write operation is done during the overlap time of a low level /CE1, /WE, /LB and/or /UB, and a high level CE2.



Low Vcc Data Retention Characteristics ($T_A = -25 \text{ to } +85 \text{ }^{\circ}\text{C}$)

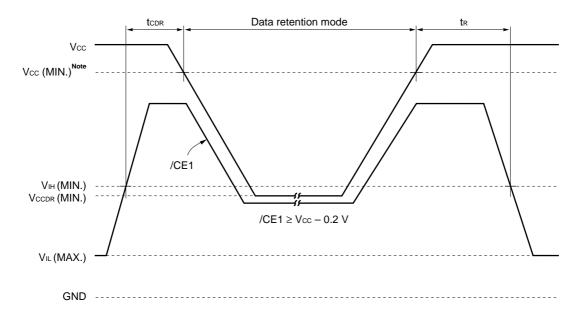
Parameter	Symbol	Test Condition	Vo	cc ≥ 2 .7	7 V	Vc	c ≥ 2. 2	2 V	Vo	c ≥ 1.8	3 V	Unit
				D4420 -B××X		•	04420 -C××X		μPD442012L -D××X			
			MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
Data retention supply voltage	Vccdr1	$/CE1 \ge Vcc - 0.2 \text{ V},$ $CE2 \ge Vcc - 0.2 \text{ V}$	2.0		3.6	1.5		3.6	1.5		3.6	V
	Vccdr2	CE2 ≤ 0.2 V	2.0		3.6	1.5		3.6	1.5		3.6	
	Vccdr3	/LB = /UB \geq Vcc $-$ 0.2 V, /CE1 \leq 0.2 V, CE2 \geq Vcc $-$ 0.2 V	2.0		3.6	1.5		3.6	1.5		3.6	
Data retention supply current	ICCDR1	$V_{CC} = 3.0 \text{ V}, /CE1 \ge V_{CC} - 0.2 \text{ V},$ $CE2 \ge V_{CC} - 0.2 \text{ V} \text{ or } CE2 \le 0.2 \text{ V}$		0.3	4		0.3	4		0.3	4	μΑ
	ICCDR2	Vcc = 3.0 V, CE2 ≤ 0.2 V		0.3	4		0.3	4		0.3	4	
	ICCDR3	$Vcc = 3.0 \text{ V}, /LB = /UB \ge Vcc - 0.2 \text{ V}, /CE1 \le 0.2 \text{ V}, CE2 \ge Vcc - 0.2 \text{ V}$		0.3	4		0.3	4		0.3	4	
Chip deselection to data retention mode	tcdr		0			0			0			ns
Operation recovery time	tr		t _{RC} Note			t _{RC} Note			t _{RC} Note			ns

Note t_{RC} : Read cycle time



Data Retention Timing Chart

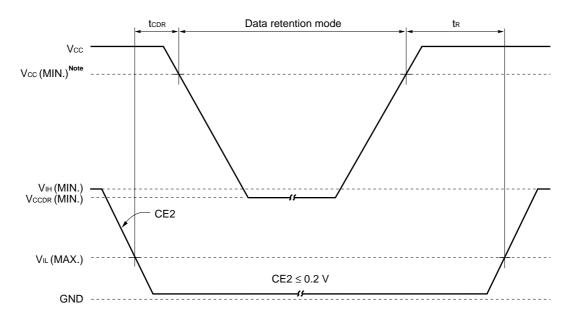
(1) /CE1 Controlled



Note B version: 2.7 V, C version: 2.2 V, D version: 1.8 V

Remark On the data retention mode by controlling /CE1, the input level of CE2 must be \geq Vcc - 0.2 V or \leq 0.2 V. The other pins (Address, I/O, /WE, /OE, /LB, /UB) can be in high impedance state.

(2) CE2 Controlled

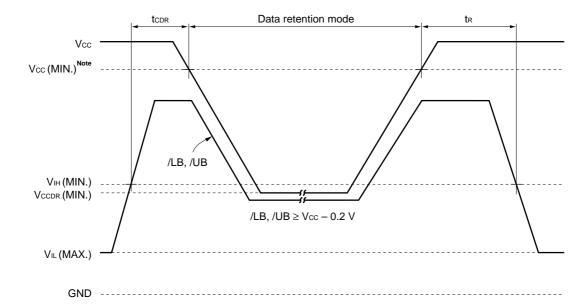


 $\textbf{Note} \quad \text{B version}: 2.7 \text{ V, C version}: 2.2 \text{ V, D version}: 1.8 \text{ V}$

Remark On the data retention mode by controlling CE2, the other pins (/CE1, Address, I/O, /WE, /OE, /LB, /UB) can be in high impedance state.

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(3) /LB, /UB Controlled



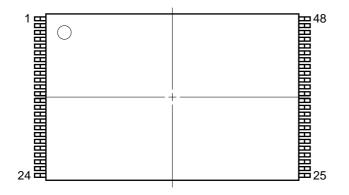
Note B version: 2.7 V, C version: 2.2 V, D version: 1.8 V

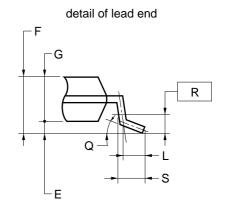
Remark On the data retention mode by controlling /LB and /UB, the input level of /CE1 and CE2 must be \geq Vcc - 0.2 V or \leq 0.2 V. The other pins (Address, I/O, /WE, /OE) can be in high impedance state.

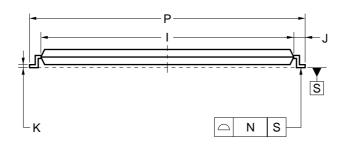


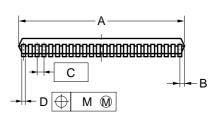
Package Drawing

48-PIN PLASTIC TSOP(I) (12x18)









NOTES

- 1. Each lead centerline is located within 0.10 mm of its true position (T.P.) at maximum material condition.
- 2. "A" excludes mold flash. (Includes mold flash: 12.4 mm MAX.)

ITEM	MILLIMETERS
A	12.0±0.1
В	0.45 MAX.
С	0.5 (T.P.)
D	0.22±0.05
E	0.1±0.05
F	1.2 MAX.
G	1.0±0.05
- 1	16.4±0.1
J	0.8±0.2
K	0.145±0.05
L	0.5
М	0.10
N	0.10
P	18.0±0.2
Q	3°+5°
R	0.25
S	0.60±0.15
	CARCY ED MILLA A

S48GY-50-MJH1-1

Recommended Soldering Conditions

Please consult with our sales offices for soldering conditions of the μ PD442012L-X.

★ Types of Surface Mount Device

 μ PD442012LGY-BxxX-MJH: 48-PIN PLASTIC TSOP (I) (12×18) (Normal bent) μ PD442012LGY-CxxX-MJH: 48-PIN PLASTIC TSOP (I) (12×18) (Normal bent) μ PD442012LGY-DxxX-MJH: 48-PIN PLASTIC TSOP (I) (12×18) (Normal bent)



[MEMO]

[MEMO]

NOTES FOR CMOS DEVICES

1 PRECAUTION AGAINST ESD FOR SEMICONDUCTORS

Note:

Strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred. Environmental control must be adequate. When it is dry, humidifier should be used. It is recommended to avoid using insulators that easily build static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work bench and floor should be grounded. The operator should be grounded using wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with semiconductor devices on it.

2 HANDLING OF UNUSED INPUT PINS FOR CMOS

Note:

No connection for CMOS device inputs can be cause of malfunction. If no connection is provided to the input pins, it is possible that an internal input level may be generated due to noise, etc., hence causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using a pull-up or pull-down circuitry. Each unused pin should be connected to VDD or GND with a resistor, if it is considered to have a possibility of being an output pin. All handling related to the unused pins must be judged device by device and related specifications governing the devices.

3) STATUS BEFORE INITIALIZATION OF MOS DEVICES

Note:

Power-on does not necessarily define initial status of MOS device. Production process of MOS does not define the initial operation status of the device. Immediately after the power source is turned ON, the devices with reset function have not yet been initialized. Hence, power-on does not guarantee out-pin levels, I/O settings or contents of registers. Device is not initialized until the reset signal is received. Reset operation must be executed immediately after power-on for devices having reset function.

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